Application No.	Applicant(s)	
10/632,380	CHU ET AL.	
Examiner	Art Unit	
 Victor V Yevsikov	2825	

SEARCHED				
Class	Subclass	Date	Examiner	
438	584,592 597,620 530,514 527,299	2/11/2004	VY	
438	301,303	2/11/2004	VY	
438	682, 486,	2/23/2004	VY	
438	527,530	2/23/2004	VY	
,				

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
			•	
same a	s above	2/23/2004	VY	

SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
MOSFET, salicide, silicide, amorphous, silicon, anneal, etch, second anneal, depth, recrystallization	2/11/2004	VY
438/682,486,527,530,597,301.ccls. and ((second near2 amorph\$4) same (anneal\$4 or (heat adj tream\$4)) same depth)	2/23/2004	VY
•		